

[illegible]

lenses for imaging the back-focal plane of the objective lens onto said phase plate such that position and tilt of the electron beam relative to an optical axis are made conjugate.

3. A transmission electron microscope comprising:

imaging lenses for imaging the back-focal plane of the objective lens onto said phase plate such that position and tilt of the electron beam relative to an optical axis are made conjugate; and

4. The transmission electron microscope of claim 3, further including an alignment coil for directing the electron beam going out of said phase plate toward lenses located after said phase plate.